



100V COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET

Product Summary

Device	BV _{DSS}	R _{DS(ON)} (Ω)max	I _D (A)max T _A = +25°C
0.4	100V	0.230 @ V _{GS} = 10V	2.1
Q1		0.300 @ V _{GS} = 4.5V	1.9
Q2	-100V	0.235 @ V _{GS} = -10V	-2.2
		0.320 @ V _{GS} = -4.5V	-1.9

Description

This new generation complementary dual MOSFET features low onresistance achievable with low gate drive.

Applications

- DC Motor Control
- Backlighting

Features

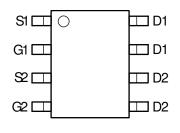
- 100V Complementary in SO-8 Package
- Low On-Resistance
- Fast Switching Speed
- Low Voltage (V_{GS} = 4.5V) Gate Drive
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

Mechanical Data

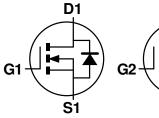
- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Finish Matte Tin Annealed over Copper Lead Frame.
 Solderable per MIL-STD-202, Method 208 (3)
- Weight: 0.074 grams (Approximate)



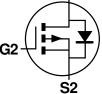




Top View



Q1 N-Channel



Q2 P-Channel

D2

Equivalent Circuit

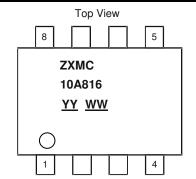
Ordering Information (Note 4)

Part Number	Reel Size (inches)	Tape Width (mm)	Quantity Per Reel	
ZXMC10A816N8TA	7	12	500	
ZXMC10A816N8TC	13	12	2,500	

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
- 2. See http://www.diodes.com/quality/lead_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.

Marking Information



ZXMC10A816 = Product Type Marking Code

YY WW = Date Code Marking

YY = Year (ex: 17 = 2017)

WW = Week (01 to 53)



Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

Parameter	Symbol	N-channel Q1	P-channel Q2	Unit
Drain-Source Voltage	V _{DSS}	100	-100	V
Gate-Source Voltage	V _{GS}	±20	±20	V
Continuous Drain Current @ V_{GS} = 10V; T_A = +25°C (Notes 6, 8) @ V_{GS} = 10V; T_A = +70°C (Notes 6, 8) @ V_{GS} = 10V; T_A = +25°C (Notes 5, 8) @ V_{GS} = 10V; T_A = +25°C (Notes 5, 9) @ V_{GS} = 10V; T_L = +25°C (Notes 8, 10)	I _D	2.1 1.7 1.7 2.0 2.3	-2.2 -1.8 -1.7 -2.0 -2.4	А
Pulsed Drain Current @ V _{GS} = 10V; T _A = +25°C (Notes 7, 8)	I _{DM}	9.4	-10.5	Α
Continuous Source Current (Body Diode) at T _A = +25°C (Notes 6, 8)	Is	3.0	-3.1	Α
Pulsed Source Current (Body Diode) at T _A = +25°C (Notes 7, 8)	I _{SM}	9.4	-10.5	Α
Avalanche Current (Note 11) L = 0.1mH	I _{AS}	1.2	-12	Α
Power Dissipation at T _A = +25°C (Notes 5, 8) Linear Derating Factor	P _D		.3).0	W mW/°C
Power Dissipation at $T_A = +25$ °C (Notes 5, 9) Linear Derating Factor	P _D	-	.8 1.2	W mW/°C
Power Dissipation at $T_A = +25$ °C (Notes 6, 8) Linear Derating Factor	P _D	2 16	.1 3.7	W mW/°C
Power Dissipation at $T_L = +25$ °C (Notes 8, 10) Linear Derating Factor	P _D	2.4 18.9	2.6 20.4	W mW/°C
Operating and Storage Temperature Range	T _J , T _{STG}	-55 to	+150	°C

Thermal Characteristics

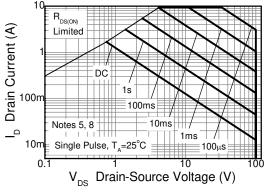
Parameter	Symbol	Valu	е	Unit
Junction to Ambient (Notes 5, 8)	$R_{ heta JA}$	100)	°C/W
Junction to Ambient (Notes 5, 9)		70		°C/W
Junction to Ambient (Notes 6, 8)	$R_{ heta JA}$	60		°C/W
Junction to Lead (Notes 8, 10)	$R_{\theta JL}$	53	49	°C/W

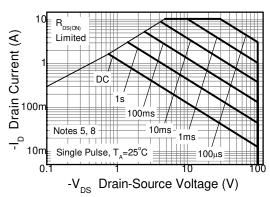
Notes:

- 5. For a device surface mounted on 25mm x 25mm x 1.6mm FR-4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition.
- 6. Same as note (5), except the device is measured at $t \le 10$ sec.
- 7. Same as note (5), except the device is pulsed with D = 0.02 and pulse width 300µs. The pulse current is limited by the maximum junction temperature.
- 8. For a dual device with one active die.
- 9. For a device with two active die running at equal power.
- 10. Thermal resistance from junction to solder-point (at the end of the drain lead); the device is operating in a steady-state condition.
- 11. I_{AS} rating is based on low frequency and duty cycles to keep $T_J = +25$ °C.

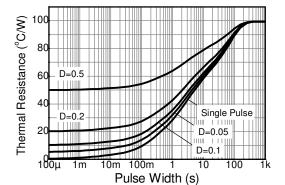


Thermal Characteristics

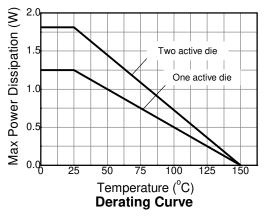




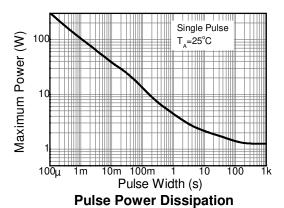
N-channel Safe Operating Area



P-channel Safe Operating Area



Transient Thermal Impedance





Electrical Characteristics Q1 N-Channel (@T_A = +25°C, unless otherwise specified.)

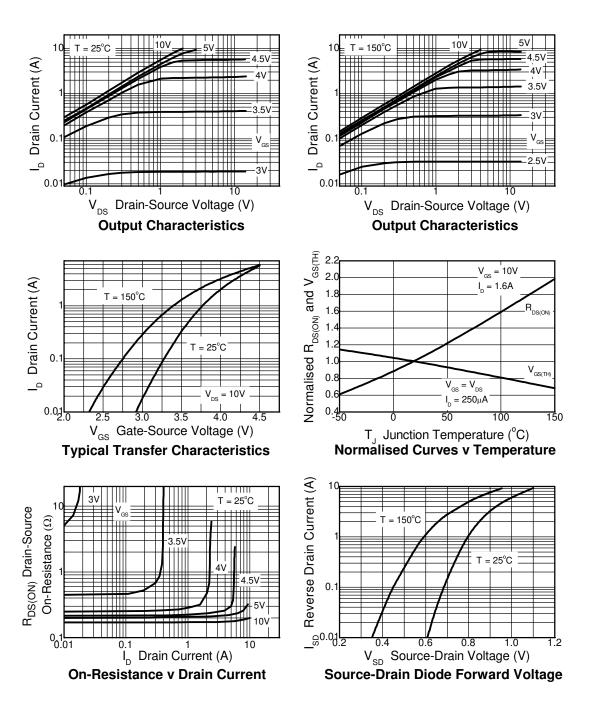
Parameter	Symbol	Min	Тур	Max	Unit	Conditions	
Static							
Drain-Source Breakdown Voltage	BV _{DSS}	100	_	1	V	$I_D = 250 \mu A, \ V_{GS} = 0 V$	
Zero Gate Voltage Drain Current	I _{DSS}	_	_	0.5	μΑ	V _{DS} = 100V, V _{GS} = 0V	
Gate-Body Leakage	I _{GSS}	_	_	100	nA	V _{GS} = ±20V, V _{DS} = 0V	
Gate-Source Threshold Voltage	V _{GS(TH)}	1.7	_	2.4	V	$I_D=250\mu A,V_{DS}=V_{GS}$	
Static Drain-Source On-State Resistance (Note 12)	R _{DS(ON)}	_	0.170 0.210	0.230 0.300	Ω	$V_{GS} = 10V, I_D = 1.0A$ $V_{GS} = 4.5V, I_D = 0.5A$	
Forward Transconductance (Notes 12, 14)	g _{fs}	_	4.8	_	S	$V_{DS} = 15V, I_D = 1.6A$	
Dynamic Capacitance (Note 14)							
Input Capacitance	Ciss	-	497	_	pF	.,,,	
Output Capacitance	Coss	l	29	1	pF	V _{DS} = 50V, V _{GS} = 0V f = 1MHz	
Reverse Transfer Capacitance	C _{rss}	-	18	_	pF	1 = 1101112	
Switching (Notes 13, 14)							
Turn-On-Delay Time	t _{D(ON)}	-	2.9	_	ns	.,,,,,	
Rise Time	t _R	l	2.1	1	ns	$V_{DD} = 50V, V_{GS} = 10V$ $V_{DD} = 1.0A$	
Turn-Off Delay Time	t _{D(OFF)}	-	12.1	_	ns	$R_{G} \cong 6.0\Omega$	
Fall Time	t _F	_	5.0	_	ns	11G = 0.012	
Gate Charge (Note 14)							
Total Gate Charge	Q_g	l	9.2	1	nC	V 50V V 40V	
Gate-Source Charge	Q_{gs}	-	1.7	_	nC	$V_{DS} = 50V$, $V_{GS} = 10V$	
Gate-Drain Charge	Q_{gd}	1	2.5	1	nC	- ID = 1.0A	
Source-Drain Diode							
Diode Forward Voltage (Note 12)	V_{SD}	-	0.85	0.95	V	$I_S = 1.7A, V_{GS} = 0V$	
Reverse Recovery Time (Note 14)	t _{RR}	_	32	_	ns	I _S = 1.7A, di/dt = 100A/μs	
Reverse Recovery Charge (Note 14)	Q _{RR}	_	40	1	nC		
Gate Resistance							
Gate Resistance	R_{G}	0		3	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1.0MHz$	

Notes:

^{12.} Measured under pulsed conditions. Pulse width ≤ 300µs; duty cycle ≤ 2%.
13. Switching characteristics are independent of operating junction temperature.
14. For design aid only, not subject to production testing.

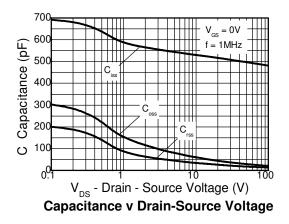


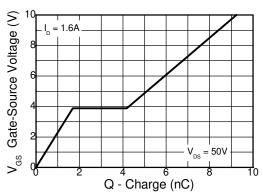
Typical Characteristics Q1 N-Channel





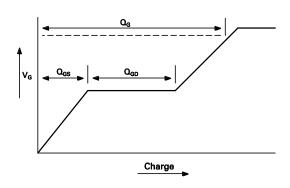
Typical Characteristics Q1 N-Channel (Cont.)

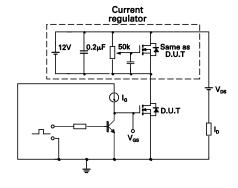




Gate-Source Voltage v Gate Charge

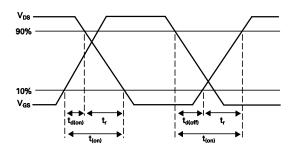
Test Circuits

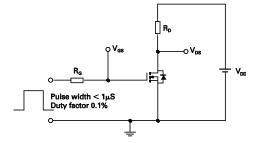




Basic gate charge waveform

Gate charge test circuit





Switching time waveforms

Switching time test circuit



Electrical Characteristics Q2 P-Channel (@T_A = +25°C, unless otherwise specified.)

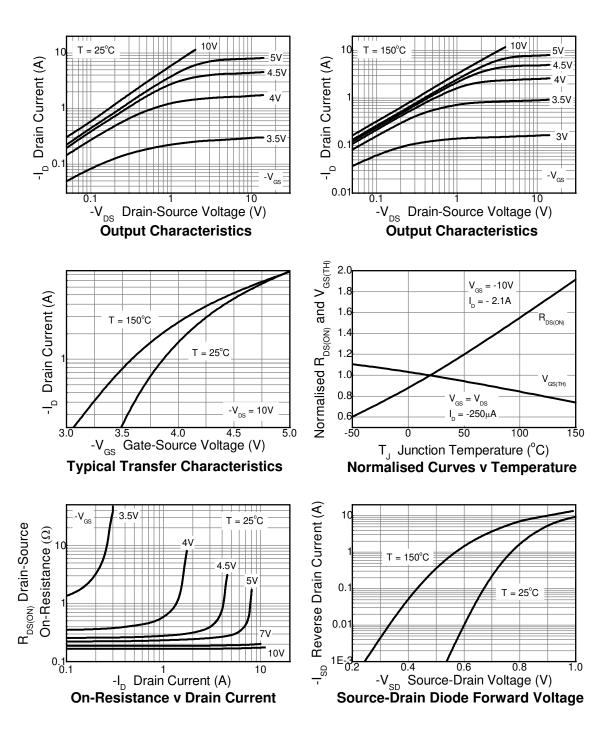
Parameter	Symbol	Min	Тур	Max	Unit	Conditions	
Static							
Drain-Source Breakdown Voltage	BV _{DSS}	-100	_	_	V	$I_D = -250 \mu A, \ V_{GS} = 0 V$	
Zero Gate Voltage Drain Current	I _{DSS}	-	_	-0.5	μΑ	$V_{DS} = -100V, V_{GS} = 0V$	
Gate-Body Leakage	I _{GSS}	_	_	-100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
Gate-Source Threshold Voltage	V _{GS(TH)}	-2.0	_	-3.0	V	$I_D = -250 \mu A, \ V_{DS} = V_{GS}$	
Static Drain-Source On-State Resistance (Note 12)	R _{DS(ON)}		0.170 0.250	0.235 0.320	Ω	$V_{GS} = -10V$, $I_D = -1.0A$ $V_{GS} = -4.5V$, $I_D = -0.5A$	
Forward Transconductance (Notes 12, 14)	g _{fs}	_	4.7	_	S	$V_{DS} = -15V, I_{D} = -2.1A$	
Dynamic Capacitance (Note 14)							
Input Capacitance	C _{iss}	l	717	_	pF	., 50,4,4, 0,4	
Output Capacitance	Coss	-	55	_	pF	$V_{DS} = -50V, V_{GS} = 0V$ f = 1MHz	
Reverse Transfer Capacitance	C _{rss}	_	46	_	pF	1 – 1101112	
Switching (Notes 13, 14)							
Turn-On-Delay Time	t _{D(ON)}	-	4.3	_	ns		
Rise Time	t _R	l	5.2	_	ns	$V_{DD} = -50V, V_{GS} = -10V$ $I_{D} = -1A$	
Turn-Off Delay Time	t _{D(OFF)}	-	20	_	ns	$R_{G} \cong 6.0\Omega$	
Fall Time	t _F	1	12	_	ns	11G = 0.012	
Gate Charge (Note 14)							
Total Gate Charge	Q_g	-	16.5	_	nC	, FOV V 10V	
Gate-Source Charge	Q _{gs}	l	2.5	_	nC	$V_{DS} = -50V, V_{GS} = -10V$ $I_{D} = -2.1A$	
Gate-Drain Charge	Q_{gd}	-	5.4	_	nC	7 ID = -2.1A	
Source-Drain Diode							
Diode Forward Voltage (Note 12)	V_{SD}	-	-0.85	-0.95	V	$I_S = -1.7A$, $V_{GS} = 0V$	
Reverse Recovery Time (Note 14)	t _{RR}		43	_	ns	1 70 41/44 1000/	
Reverse Recovery Charge (Note 14)	Q _{RR}		77	_	nC	I _S = -1.7A, di/dt = 100A/μs	
Gate Resistance							
Gate Resistance	R _G	0	_	100	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$	

Notes:

^{12.} Measured under pulsed conditions. Pulse width ≤ 300µs; duty cycle ≤ 2%.
13. Switching characteristics are independent of operating junction temperature.
14. For design aid only, not subject to production testing.

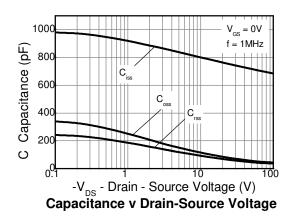


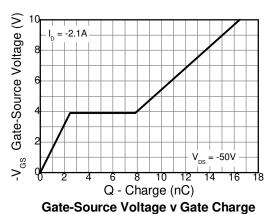
Typical Characteristics Q2 P-Channel



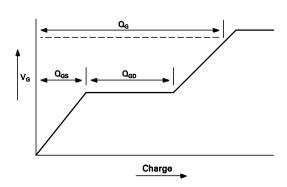


Typical Characteristics Q2 P-Channel (Cont.)

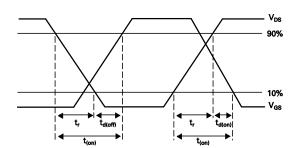




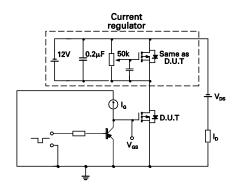
Test Circuits



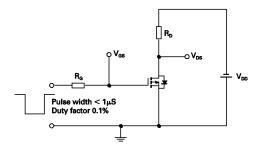




Switching time waveforms



Gate charge test circuit



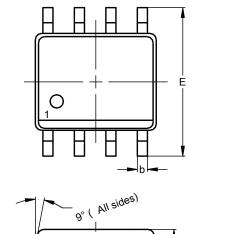
Switching time test circuit

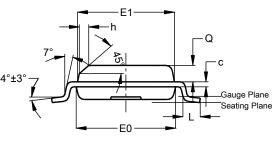


Package Outline Dimensions

Please see http://www.diodes.com/package-outlines.html for the latest version.

SO-8



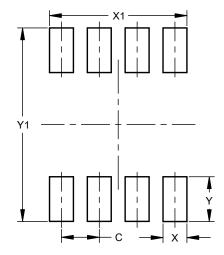


SO-8					
Dim	Min	Max	Тур		
Α	1.40	1.50	1.45		
A 1	0.10	0.20	0.15		
b	0.30	0.50	0.40		
С	0.15	0.25	0.20		
D	4.85	4.95	4.90		
Е	5.90	6.10	6.00		
E1	3.80	3.90	3.85		
E0	3.85	3.95	3.90		
е			1.27		
h	-		0.35		
L	0.62	0.82	0.72		
Q	0.60	0.70	0.65		
All Dimensions in mm					

Suggested Pad Layout

Please see http://www.diodes.com/package-outlines.html for the latest version.

SO-8



Dimensions	Value (in mm)		
C	1.27		
Х	0.802		
X1	4.612		
Υ	1.505		
Y1	6.50		



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